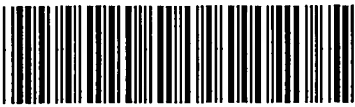


<b>Search Notes</b>  	<b>Application/Control No.</b>  10502423	<b>Applicant(s)/Patent Under Reexamination</b>  BASE ET AL.
	<b>Examiner</b>  Yeh, Eueng-nan	<b>Art Unit</b>  2624

<b>SEARCHED</b>			
<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>

<b>SEARCH NOTES</b>		
<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
(382/135) text search - see search outputs	2007/11/01	ey
EAST text search - see search outputs	2007/10/31	ey
PALM inventor search -see search outputs	2007/10/31	ey
USPTO PLUS search - see search outputs	2007/11/07	ey
IEEE Xplore search - see search outputs	2007/11/28	ey

<b>INTERFERENCE SEARCH</b>			
<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>